

Thick Film Chip Resistor FRC Series



Application

- Entertainment : Stereo, TV tuners , Tape recorder
- Appliance: Air conditioner, Refrigerator
- Computer & relative products : Main board, PDA
- Communication equipment: Cell phone, Fax machine
- Power equipment: Power supply , II Lumination equipment
- Measuring instrument: Electric meter, Navigation equipment

Features

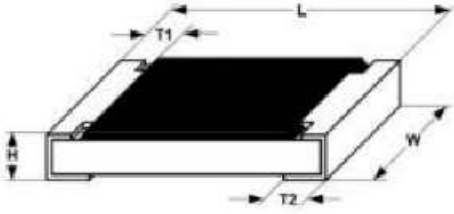
- small size and light weight
- Reliability, high quality

Parts Number Explanation

Example FRC1206F1001 TSD

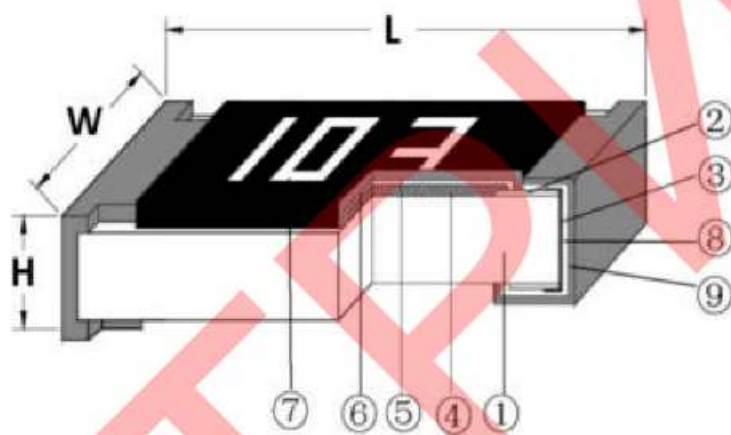
F	R	C	1206	F	1001	T	S	D
FOJAN	R: Resistor C: Capacitor L: Inductor D: Diode A: Audion	C: Normal P: Hi-Power L: Lowohmic A: Array S: Surge H: Hi-Precision V: Hi-Voltage Q: Auto-motive R: Anti-sulfur M: Metal D: LED	0201 0402 0603 0805 1206 1210 1218 1812 2010 2512	B: ±0.1% C: ±0.25% D: ±0.5% F: ±1% J: ±5% P: Jumper	±5%: E24 3-digits+blank 102=1KΩ 1R0=1Ω ±1%&Below : E24+E96 : 4-digits 1001=1KΩ 1R00=1Ω	T: 7 inch reel Q: 10 inch reel R: 13 inch reel B: Bulk	S : Sn C : Cu A : Au	N: Normal D : LED
Company code	Type code	Functional code	Size code	Tolerance code	Resistance code	Packaging code	Termination code	Special Case

Dimension

dimension					
Type	L	W	H	T1	T2
0201	0.60±0.03	0.30±0.03	0.23±0.03	0.10±0.05	0.15±0.05
0402	1.00±0.05	0.50±0.05	0.35±0.05	0.20±0.10	0.25±0.10
0603	1.60±0.10	0.80±0.10	0.45±0.10	0.25±0.15	0.25±0.15
0805	2.00±0.10	1.25±0.10	0.50±0.10	0.35±0.20	0.35±0.20
1206	3.10±0.10	1.60±0.10	0.55±0.10	0.45±0.20	0.40±0.20
1210	3.10±0.10	2.60±0.15	0.55±0.10	0.45±0.15	0.50±0.20
1218	3.10±0.10	4.60±0.10	0.55±0.10	0.45±0.20	0.40±0.20
1812	4.50±0.20	3.10±0.20	0.55±0.10	0.55±0.20	0.70±0.20
2010	5.00±0.10	2.50±0.15	0.55±0.10	0.45±0.15	0.50±0.20
2512	6.35±0.10	3.10±0.15	0.55±0.10	0.60±0.20	0.50±0.20

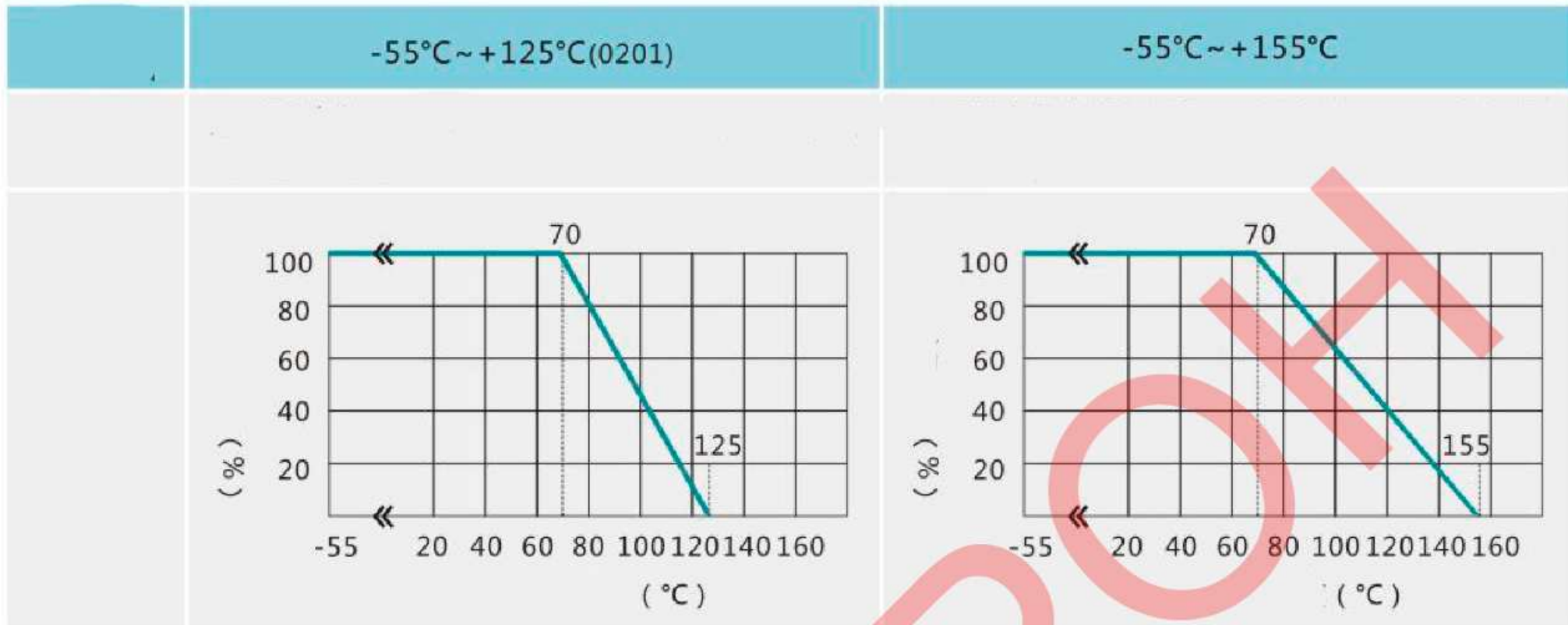
(unit) : mm

Construction)



NO.	construction	Major material
1	Ceramic substrate	Al ₂ O ₃
2	Conductive layer	Ag
3	Side conductive layer	NiCr
4	Resistive layer	RuO ₂ + glass
5	Inner protective layer	Glass
6	Outer Protective layer	Epoxy
7	Marking	Epoxy
8	Ni plating layer	Ni
9	Sn plating layer	Matte Tin

Derating Curve



Electrical characteristics

Type	0201	0402	0603	0805	1206	1210	1218	1812	2010	2512
Dielectric Withstanding Voltage	-	100V	100V	300V	500V	500V	500V	500V	500V	500V
Resistance Value of Jumper $\pm 1\%$	-	<30m Ω	<30m Ω	<30m Ω	<30m Ω	<30m Ω	<30m Ω	<30m Ω	<30m Ω	<30m Ω
Resistance Value of Jumper $\pm 5\%$	<50m Ω	<50m Ω	<50m Ω	<50m Ω	<50m Ω	<50m Ω	<50m Ω	<50m Ω	<50m Ω	<50m Ω
Rated Current of Jumper	0.5A	1A	1A	2A	2A	2A	6A	2A	2A	2A
Max Current of Jumper	1A	2A	2A	5A	10A	10A	10A	10A	10A	10A

Standard Electrical Specifications

Type	Power Rating at 70°C	Max. RCWV	Max. Overload Voltage	(PPM/°C)	Resistance Range
0201	1/20W	25V	50V	± 400	1Ω~10Ω
				± 200	10Ω~10MΩ
0402	1/16W	50V	100V	±200	1Ω~10Ω
				± 100	10MΩ~100MΩ
0603	1/10W	75V	150V	± 200	10Ω~10MΩ
				± 100	10MΩ~100MΩ
0805	1/8W	150V	300V	± 200	1Ω~10Ω
				± 100	10MΩ~100MΩ
1206	1/4W	200V	400V	± 200	10Ω~10MΩ
				± 100	1Ω~10Ω
1210	1/3W	200V	400V	± 200	10MΩ~100MΩ
				± 100	10Ω~10MΩ
1218	1W	200V	500V	± 200	1Ω~10Ω
				± 100	10Ω~1MΩ
1812	3/4W	200V	400V	± 200	1Ω~10Ω
				± 100	10MΩ~100MΩ
2010	3/4W	200V	400V	± 200	1Ω~10Ω
				± 100	10MΩ~100MΩ
2512	1W	200V	400V	± 200	10Ω~10MΩ
				± 100	1Ω~10Ω

For non-standard parts, please contact our sales dept.

Performance Specifications

Item	Test Methods	Test Conditions	Specification
Temperature Coefficient	JIS C 5201 4.8	$TCR = \frac{R - R_0}{(t - t_0) R_0} \times 10^6 \text{ (ppm)}$ $R_0 \text{ (resistance at room temperature)}$ $R \text{ (resistance at } 125^\circ\text{C or } -55^\circ\text{C)}$ $t_0 \text{ (room temperature)}$ $t \text{ (test temperature } 125^\circ\text{C or } -55^\circ\text{C)}$	0201 : $1\Omega \leq R \leq 10\Omega$: $\pm 400 \text{ PPM}/^\circ\text{C}$ $10\Omega < R \leq 10\text{M}\Omega$: $\pm 200 \text{ PPM}/^\circ\text{C}$ 0402~2512 : $1\Omega \leq R \leq 10\Omega$: $\pm 200 \text{ PPM}/^\circ\text{C}$ $10\Omega < R \leq 10\text{M}\Omega$: $\pm 100 \text{ PPM}/^\circ\text{C}$ $10\text{M}\Omega < R \leq 100\text{M}\Omega$: $\pm 200 \text{ PPM}/^\circ\text{C}$
Short-time overload	JIS C 5201 4.13	Applied 2.5 times of rated voltage for 5 second. Measure the variation of resistance.	$\pm(1.00\% + 0.05\Omega)$
Solderability	JIS C 5201 4.17	Dip the terminal in a flux and then dip into a soldering bath at $245 \pm 5^\circ\text{C}$ for $3 \pm 0.5\text{sec}$.	(> 95% coverage)
Resistto soldering heat	JIS C 5201 4.18	Dip the terminal in a flux and then dip into a soldering bath at $260 \pm 5^\circ\text{C}$ for $10 \pm 0.5\text{sec}$. Measure the variation of resistance.	$\pm(1.00\% + 0.05\Omega)$
Insulation resistance	JIS C 5201 4.6	Applied the dielectric withstanding voltage on the center of body for $60 \pm 5\text{seconds}$. Then measure insulation resistance.	>10GΩ
Dielectric withstanding voltage	JIS C 5201 4.7	Applied the dielectric withstanding voltage on the center of body for $60 \pm 5\text{seconds}$.	No evidence of flashover, mechanical damage arcing or insulation breakdown

Item	Test Methods	Test Conditions	Specification
Terminalbending	JIS C 5201 4.33	Specimen shall be mounted on test board, then bend the board and maintained for 20±1s. the distance of bending is 5+0.2/0 mm for resistors which size no larger than 1206 or 2+0.2/0 mm which size larger than 1206. Measure the variation of resistance.	±(1.00% +0.05Ω)
Temperature Cycling	JIS C 5201 4.19	Put specimen in a chamber which temperature can be changed to 155±2°C or -55±3°C, repeated 5 times. Measure the variation of resistance.	±(2.00% +0.05Ω)
Humidity	JIS C 5201 4.24	Put the specimen in a chamber at 40±2°C temperature and 90~95% relative humidity, then applied rated voltage for 1.5H and rested for 0.5H repeatedly till total test time is 1000 ^{+48/0} H. Measure the variation of resistance.	±(2.00% +0.05Ω)
Load life	JIS C 5201 4.25.1	Put the specimen in a chamber at 70±2°C temperature, ON TIME:1.5H , OFF TIME:0.5H , and applied rated voltage for 1000 ^{+24/0} H. Measure the variation of resistance.	±(2.00% +0.05Ω)
Moisture resistance	MIL-STD-202 METHOD 106	25°C~65°C,90~100%RH, 2.5H; 65°C 90~100%RH, 3H; 65°C~25°C 80~100%RH, 2.5H, 10 cycles, Measurement at 24±4 hours after test conclusion.	±(2.00% +0.05Ω)